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Ali M. Khounsary
Gert E. van Dorssen
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Contents

v	Authors
vii	Conference Committee

SESSION 1 NOVEL LABORATORY X-RAY SOURCES I

9964 02	A compact, coherent light source system architecture [9964-2]
9964 04	Advanced controls for light sources [9964-4]

SESSION 2 NOVEL LABORATORY X-RAY SOURCES II

9964 05	Image-based characterization of microfocus x-ray target failure [9964-5]
9964 06	Simulations of laser undulators [9964-6]
9964 08	A case for ZnO nanowire field emitter arrays in advanced x-ray source applications [9964-8]

SESSION 3 LABORATORY-BASED X-RAY OPTICS

9964 09	Development of polycapillary x-ray optics for x-ray spectroscopy [9964-9]
9964 0A	Large field-of-view asymmetric masks for high-energy x-ray phase imaging with standard x-ray tube [9964-10]

SESSION 4 LABORATORY-BASED X-RAY APPLICATIONS

9964 0E	Simulation tools for analyzer-based x-ray phase contrast imaging system with a conventional x-ray source [9964-13]
9964 0F	X-ray phase scanning setup for non-destructive testing using Talbot-Lau interferometer [9964-14]
9964 0G	High-resolution radiography of thick steel objects using an all-laser-driven MeV-energy x-ray source [9964-15]
9964 0I	Laboratory-based x-ray phase-contrast tomography enables 3D virtual histology [9964-19]

POSTER SESSION

- 9964 0J **Laboratory and synchrotron tests of two-dimensional parabolic x-ray compound refractive lens made of single-crystal diamond [9964-17]**

Authors

Numbers in the index correspond to the last two digits of the six-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first four digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Adams, Bernhard W., 09	Robinson, Vance S., 05, 08
Astolfo, A., 0A	Ross, William R., 05
Attenkofer, Klaus, 09	Sabia, E., 02
Bachche, S., 0F	Salditt, Tim, 0I
Banerjee, Sudeep, 0G	Snigirev, A., 0J
Barannikov, A., 0J	Snigireva, I., 0J
Bergkvist, Magnus, 08	Spassovsky, I. P., 02
Biedron, S. G., 02, 04, 06	Stoupin, Stanislav, 0E
Blank, V. D., 0J	Terentiev, S. A., 0J
Bond, Justin L., 09	Töpperwien, Mareike, 0I
Brankov, J. G., 0E	Umstadter, Donald, 0G
Caudevilla, Oriol, 0E	van der Slot, P. J. M., 02
Chen, Daokun, 08	Verman, Boris, 0E
Chen, Jun, 08	Yan, Wenchao, 0G
Chen, Shouyuan, 0G	Zhang, Ping, 0G
Craven, Christopher A., 09	Zhao, Baozhen, 0G
Cremer, Till, 09	Zholudev, S. I., 0J
Dattoli, G., 02	Zhou, Wei, 0E
Denisov, V. N., 0J	Zverev, D., 0J
DiPalma, E., 02	
Edelen, A. L., 04	
Einstein, J. E., 02, 06	
Endrizzi, M., 0A	
Fruhling, Colton, 0G	
Golovin, Grigory, 0G	
Haden, Daniel, 0G	
Haig, I., 0A	
Huang, Mengbing, 08	
Kageyama, M., 0F	
Kato, K., 0F	
Koike, T., 0F	
Kornilov, N. V., 0J	
Krenkel, Martin, 0I	
Kuribayashi, M., 0F	
Martyushov, S. Yu., 0J	
Milton, S. V., 02, 04, 06	
Minot, Michael J., 09	
Momose, A., 0F	
Nonoguchi, M., 0F	
Olivo, A., 0A	
O'Mahony, Aileen, 09	
Petrillo, V., 02	
Polikarpov, M., 0J	
Polyakov, S. N., 0J	
Popecki, Mark A., 09	
Price, B., 0A	
Quade, Felix, 0I	
Raber, Thomas, 05	
Rau, J. V., 02	

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